


<b>Search Notes</b>  	<b>Application/Control No.</b>  10670787	<b>Applicant(s)/Patent Under Reexamination</b>  HAN ET AL.
	<b>Examiner</b>  Han, Jason M	<b>Art Unit</b>  2875

SEARCHED			
Class	Subclass	Date	Examiner
362	29-30, 97, 260	11/14/2007	JMH
349	70	11/14/2007	JMH

SEARCH NOTES		
Search Notes	Date	Examiner
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	10/25/2006	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB) - See Printout	5/8/2007	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	11/14/2007	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	6/2/2008	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	10/27/2008	JMH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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